

# HQ:NSC35/tipless/AI BS

## Tipless AFM Probe with 3 Different Soft Tapping Mode AFM Cantilevers

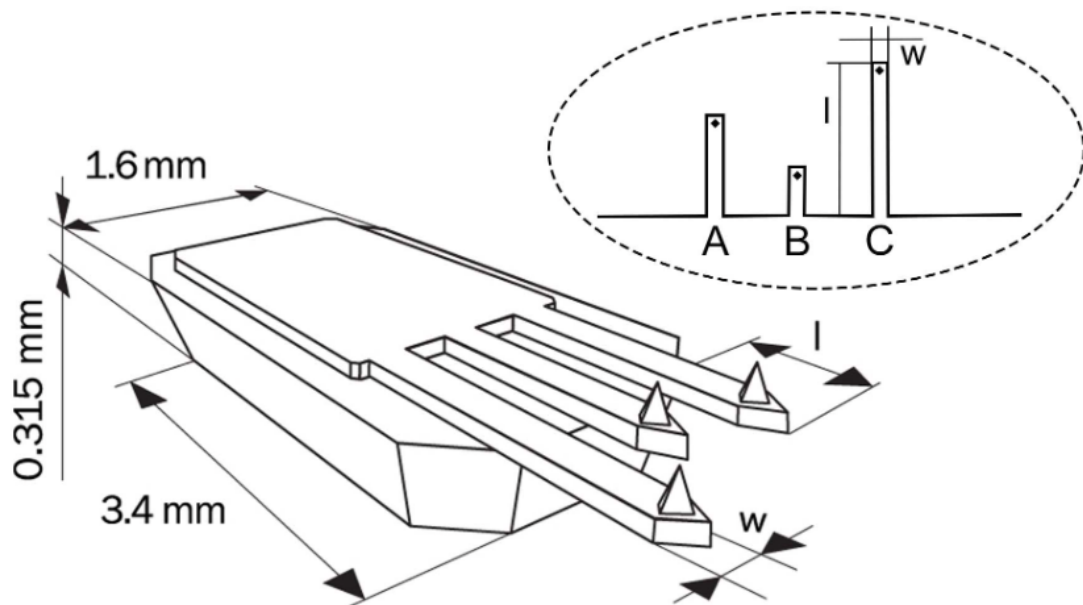
AFM probes of the HQ:NSC35 series have three different tipless soft tapping mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

The aluminum reflective coating enhances the laser reflectivity of the AFM cantilevers by approximately 2.5 times.

### Coating

Reflective Aluminum



## AFM Probe Specifications

### AFM Tip

SHAPE
Tipless

### AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	8.9 N/m (2.7 – 24 N/m)*	205 kHz (130 – 290 kHz)*	110 $\mu\text{m}$ (1 – 115 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*
Cantilever B	Beam	16 N/m (4.8 – 44 N/m)*	300 kHz (185 – 430 kHz)*	90 $\mu\text{m}$ (1 – 95 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*
Cantilever C	Beam	5.4 N/m (1.7 – 14 N/m)*	150 kHz (95 – 205 kHz)*	130 $\mu\text{m}$ (1 – 135 $\mu\text{m}$ )*	35 $\mu\text{m}$ (32 – 38 $\mu\text{m}$ )*	2 $\mu\text{m}$ (1.5 – 2.5 $\mu\text{m}$ )*

\* typical values